Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination
10/816,450	CHUN ET AL.
Examiner	Art Unit

Benjamin P. Geib

2181

SEARCHED					
Class	Subclass	Date	Examiner		
345	503	9/26/2007	BPG		
712	245	9/26/2007	BPG		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH   (INCLUDING SEAR	NOTES CH STRATEGY	
	DATE	EXMR
EAST search	9/26/2007	BPG
NPL search (IEEE Xplore)	9/26/2007	BPG
Inventor name search	9/26/2007	BPG